

2877



[10191/2066]

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s) : Pawel DRABAREK
 Serial No. : 09/990,207
 Filed : November 20, 2001
 For : INTERFEROMETRIC MEASURING DEVICE
 Examiner : Michael A. Lyons
 Group Art Unit : 2877

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 Commissioner for Patents
 P.O. Box 1450
 Alexandria, VA 22313-1450

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19 June 2003
 Michelle M. Camiaux (Reg. No. 36,098)

TRANSMITTAL

SIR:

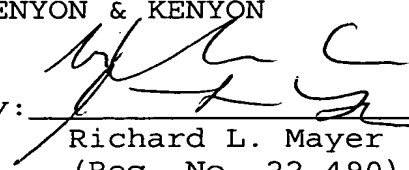
Please find an Amendment transmitted herewith for filing in the above-identified patent application.

No fee is believed to be required. However, if any fee is required, please use Deposit Account No. 11-0600. A duplicate copy of this transmittal letter is enclosed for that purpose.

Respectfully submitted,

KENYON & KENYON

Dated: 19 June 2003

By: 
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Date 19 June 2003 Atty's Reg. # 36,098

Atty's Signature

MICHELLE M. CARNIAUX
KENYON & KENYON

AMENDMENT

SIR:

This paper addresses the Office Action dated April 10, 2003. Kindly amend the above-identified application as set forth below.

IN THE SPECIFICATION:

Please amend the specification as follows:

On page 1, please replace the paragraph beginning on line 2 with the following:

--The present invention is directed to an interferometric measuring device having a probe part and an optical fiber. The measuring device is for measuring surface characteristics, shapes, distances, and distance variations, e.g., vibrations, in particular in narrow, hollow spaces of measuring objects.--

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